



### Features

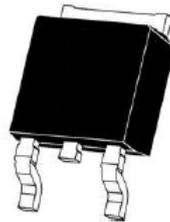
- Very Low On-resistance  $R_{DS(on)}$
- Low  $C_{rss}$
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

### Product Summary

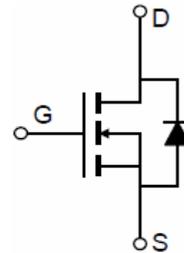
$V_{DS}$	30	V
$R_{DS(on),Typ} @ V_{GS}=10\text{ V}$	2.6	m $\Omega$
$I_D$	120	A

### Application

- PWM Application
- Load Switch
- Power Management



TO-252-2L top view



Schematic diagram

### Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	30N120KQ	Units
$V_{DSS}$	Drain-Source Voltage	30	V
$I_D$	Drain Current - Continuous ( $T_C = 25^\circ\text{C}$ )	120	A
	- Continuous ( $T_C = 100^\circ\text{C}$ )	78	A
$I_{DM}$	Drain Current - Pulsed (Note 1)	480	A
$V_{GSS}$	Gate-Source Voltage	$\pm 20$	V
$E_{AS}$	Single Pulsed Avalanche Energy (Note 2)	156	mJ
$P_D$	Power Dissipation ( $T_C = 25^\circ\text{C}$ )	89	W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.4	$^\circ\text{C/W}$
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$
$T_L$	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	300	$^\circ\text{C}$

**Electrical Characteristics**  $T_C = 25^\circ\text{C}$  unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
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**Off Characteristics**

$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$	30	--	--	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 30\text{ V}, V_{GS} = 0\text{ V}$	--	--	1	$\mu\text{A}$
$I_{GSSF}$	Gate-Body Leakage Current, Forward	$V_{GS} = 20\text{ V}, V_{DS} = 0\text{ V}$	--	--	100	nA
$I_{GSSR}$	Gate-Body Leakage Current, Reverse	$V_{GS} = -20\text{ V}, V_{DS} = 0\text{ V}$	--	--	-100	nA

**On Characteristics**

$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$	1.0	1.5	2.5	V
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = 10\text{ V}, I_D = 20\text{ A}$	--	2.6	3.1	m $\Omega$
		$V_{GS} = 4.5\text{ V}, I_D = 15\text{ A}$	--	3.5	4.5	

**Dynamic Characteristics**

$C_{iss}$	Input Capacitance	$V_{DS} = 15\text{ V}, V_{GS} = 0\text{ V},$ $f = 1.0\text{ MHz}$	--	3573	-	pF
$C_{oss}$	Output Capacitance		--	390	-	pF
$C_{riss}$	Reverse Transfer Capacitance		--	353	-	pF

**Switching Characteristics**

$t_{d(on)}$	Turn-On Delay Time	$V_{GS} = 10\text{ V}, V_{DS} = 15\text{ V},$ $R_L = 3\text{ }\Omega, I_D = 30\text{ A}$ (Note 3)	--	14	--	ns
$t_r$	Turn-On Rise Time		--	18	--	ns
$t_{d(off)}$	Turn-Off Delay Time		--	40	--	ns
$t_f$	Turn-Off Fall Time		--	12	--	ns
$Q_g$	Total Gate Charge	$V_{DS} = 15\text{ V}, I_D = 30\text{ A},$ $V_{GS} = 10\text{ V}$ (Note 3)	--	72	--	nC
$Q_{gs}$	Gate-Source Charge		--	46	--	nC
$Q_{gd}$	Gate-Drain Charge		--	13	--	nC

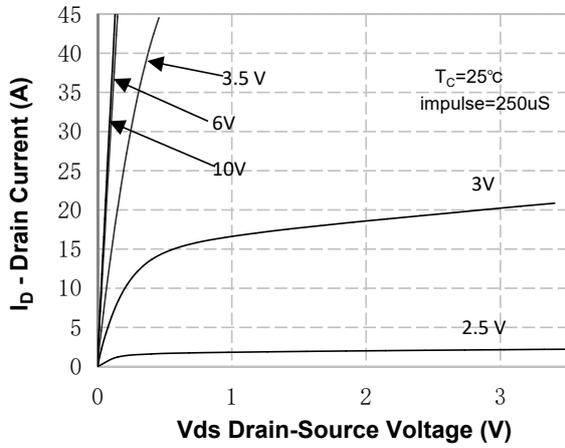
**Drain Source Diode Characteristics and Maximum Ratings**

$I_S$	Maximum Continuous Drain-Source Diode Forward Current	--	--	120	A
$I_{SM}$	Maximum Pulsed Drain-Source Diode Forward Current	--	--	480	A
$V_{SD}$	Drain to Source Diode Forward Voltage, $V_{GS} = 0\text{ V}, I_{SD} = 30\text{ A}, T_J = 25^\circ\text{C}$	--	0.7	1.2	V
$T_{rr}$	Reverse recovery time, $I_F = 30\text{ A}, di/dt = 100\text{ A}/\mu\text{s}$		48		ns
$Q_{rr}$	Reverse recovery charge, $I_F = 30\text{ A}, di/dt = 100\text{ A}/\mu\text{s}$		80		nC

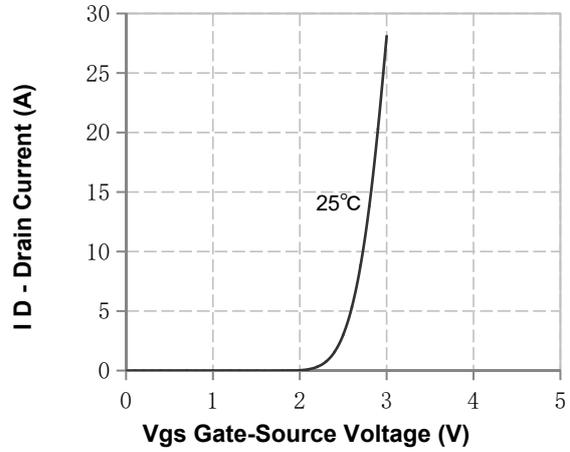
**Notes:**

1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
2. EAS condition:  $T_J = 25^\circ\text{C}, V_{DD} = 15\text{ V}, V_G = 10\text{ V}, R_G = 25\text{ }\Omega, L = 0.5\text{ mH}, I_{AS} = 25\text{ A}$
3. Pulse Test: Pulse Width  $\leq 300\text{ }\mu\text{s}$ , Duty Cycle  $\leq 0.5\%$

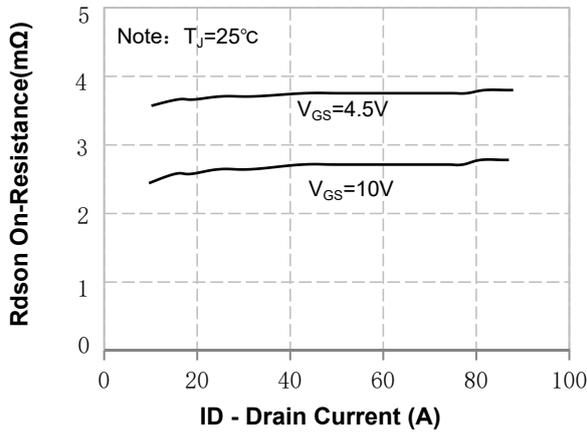
**N- Channel Typical Characteristics**



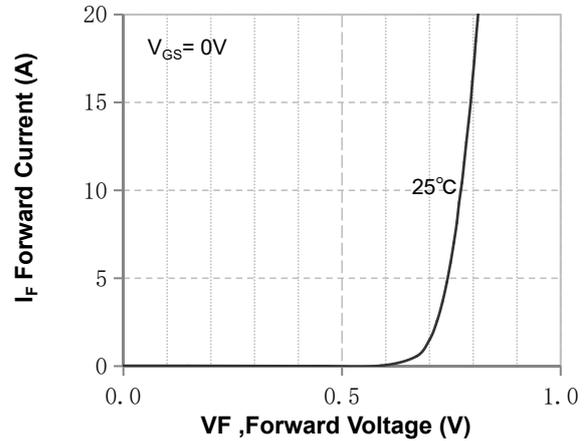
**Figure 1. On-Region Characteristics**



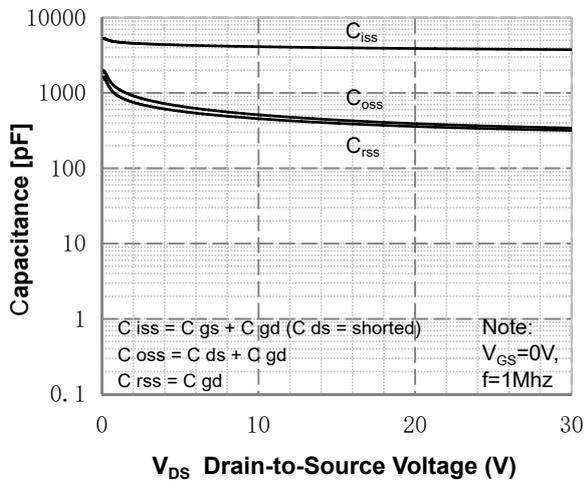
**Figure 2. Transfer Characteristics**



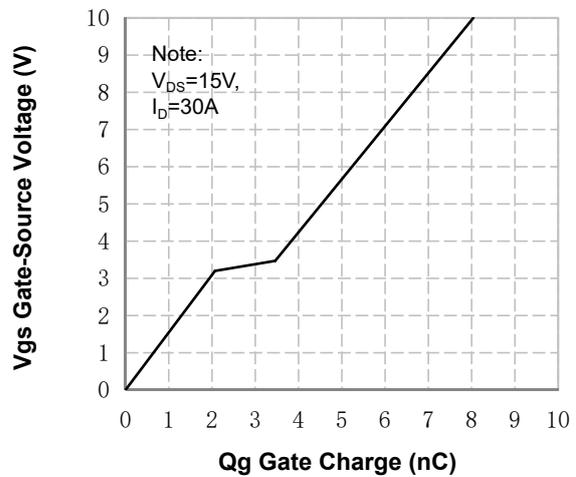
**Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage**



**Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature**



**Figure 5. Capacitance Characteristics**



**Figure 6. Gate Charge Characteristics**

N- Channel Typical Characteristics (Continued)

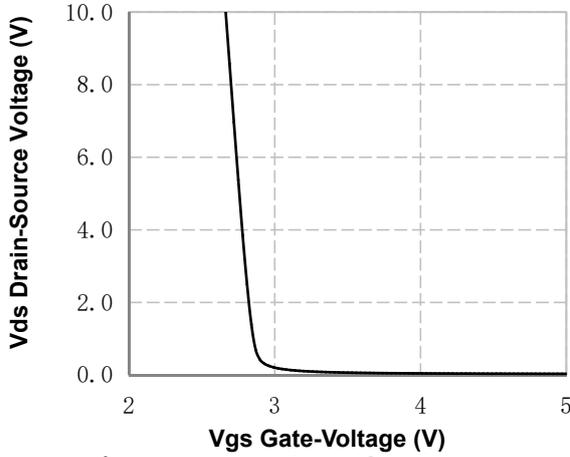


Figure 7. Vds Drain-Source Voltage vs Gate Voltage

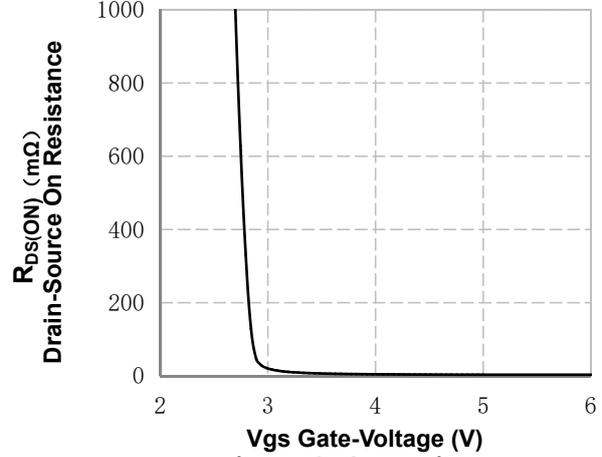


Figure 8. On-Resistance vs Gate Voltage

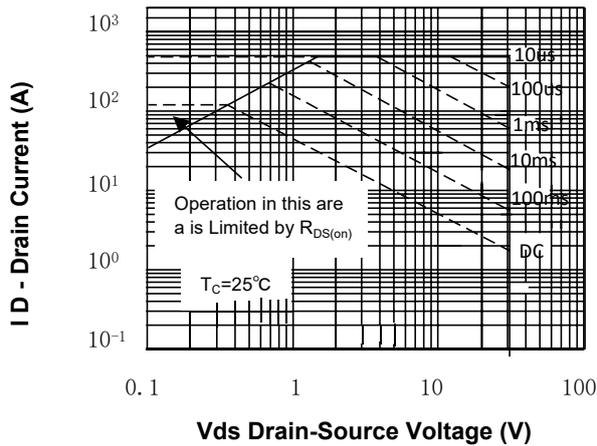


Figure 9. Maximum Safe Operating Area

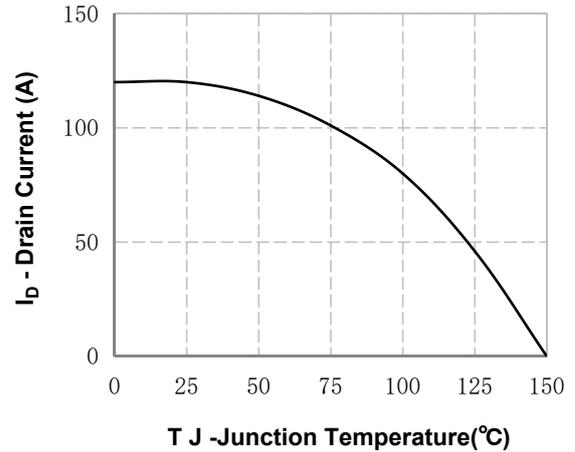


Figure 10. Maximum Continuous Drain Current vs Temperature

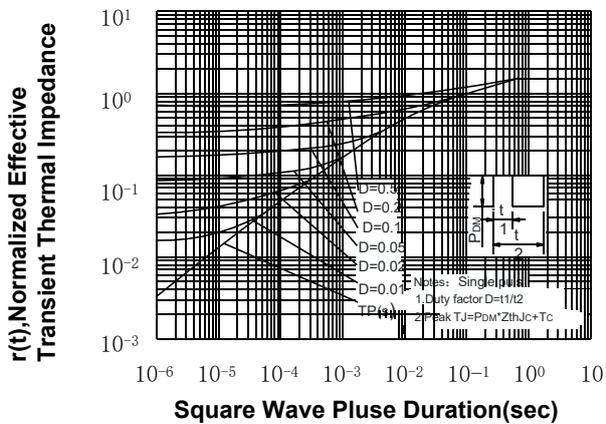
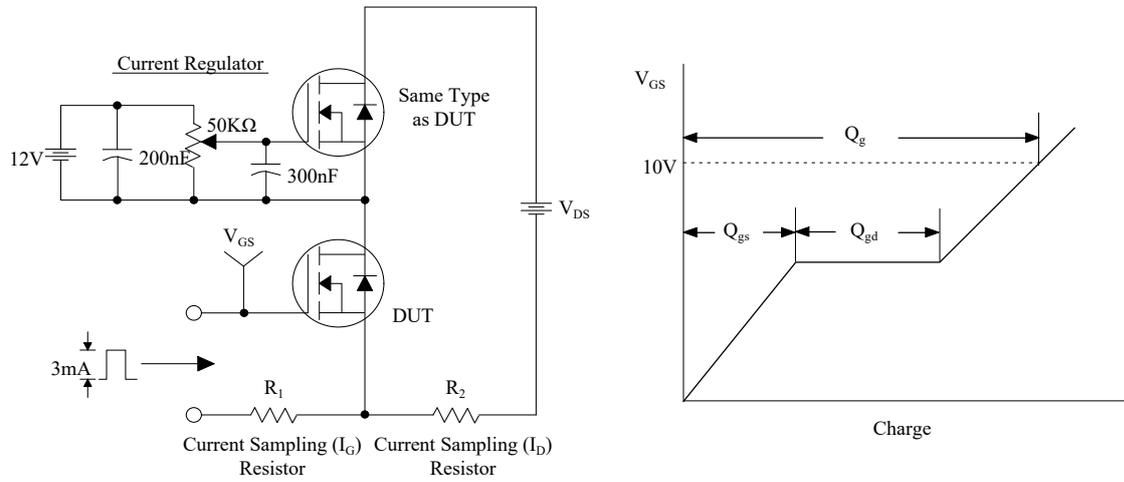
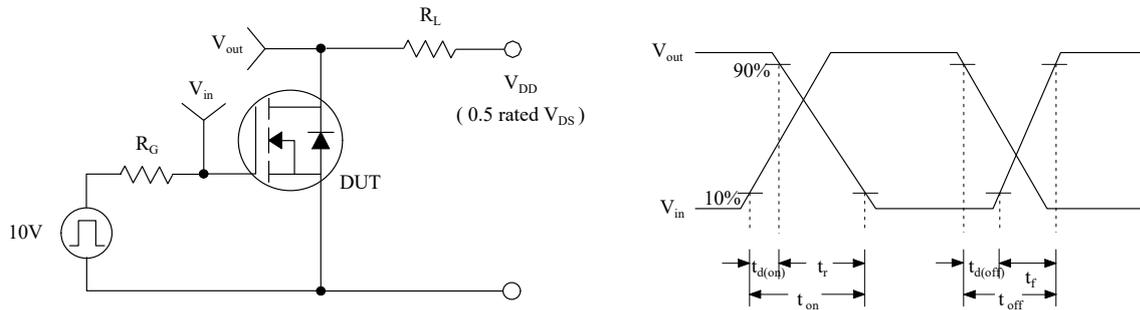


Figure 11. Transient Thermal Response Curve

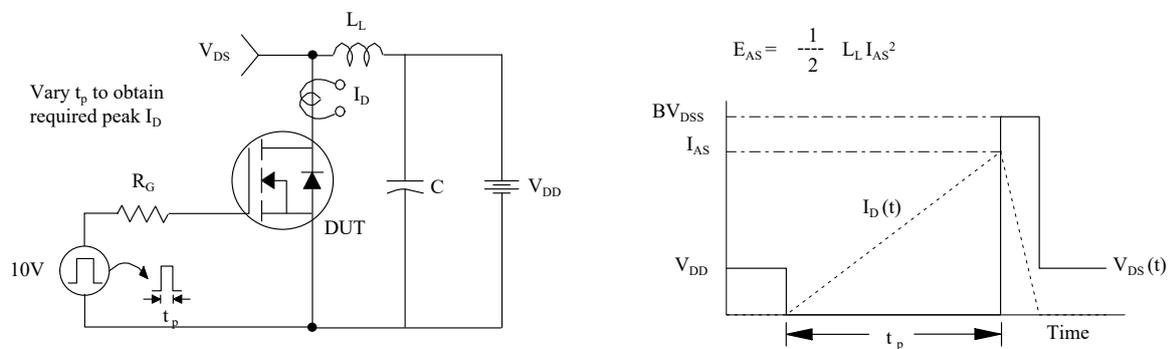
### Gate Charge Test Circuit & Waveform



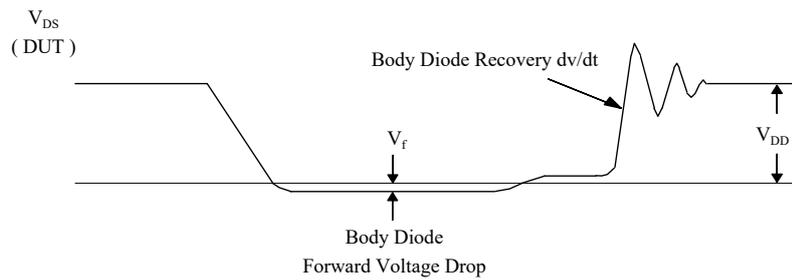
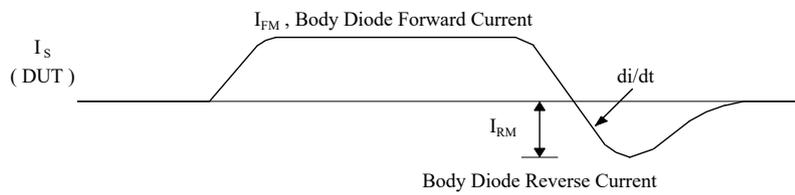
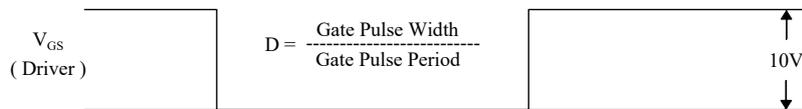
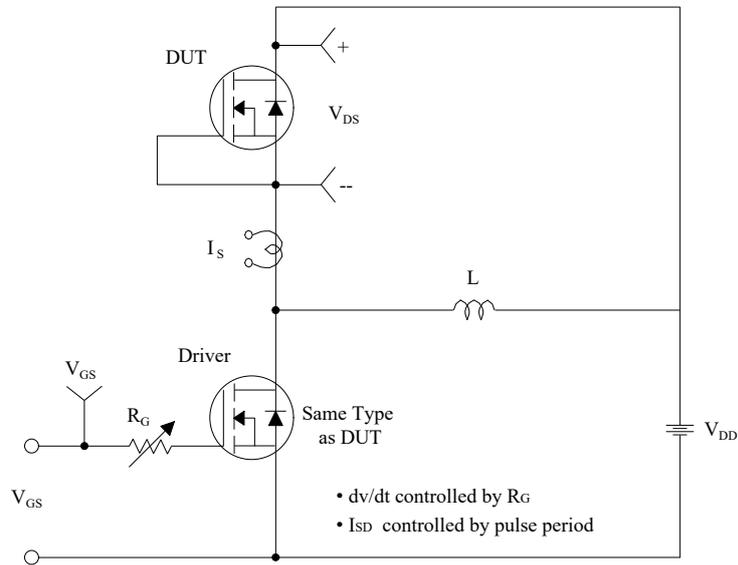
### Resistive Switching Test Circuit & Waveforms



### Unclamped Inductive Switching Test Circuit & Waveforms

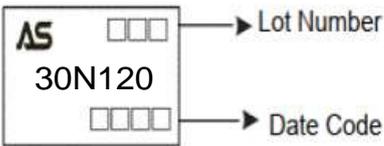


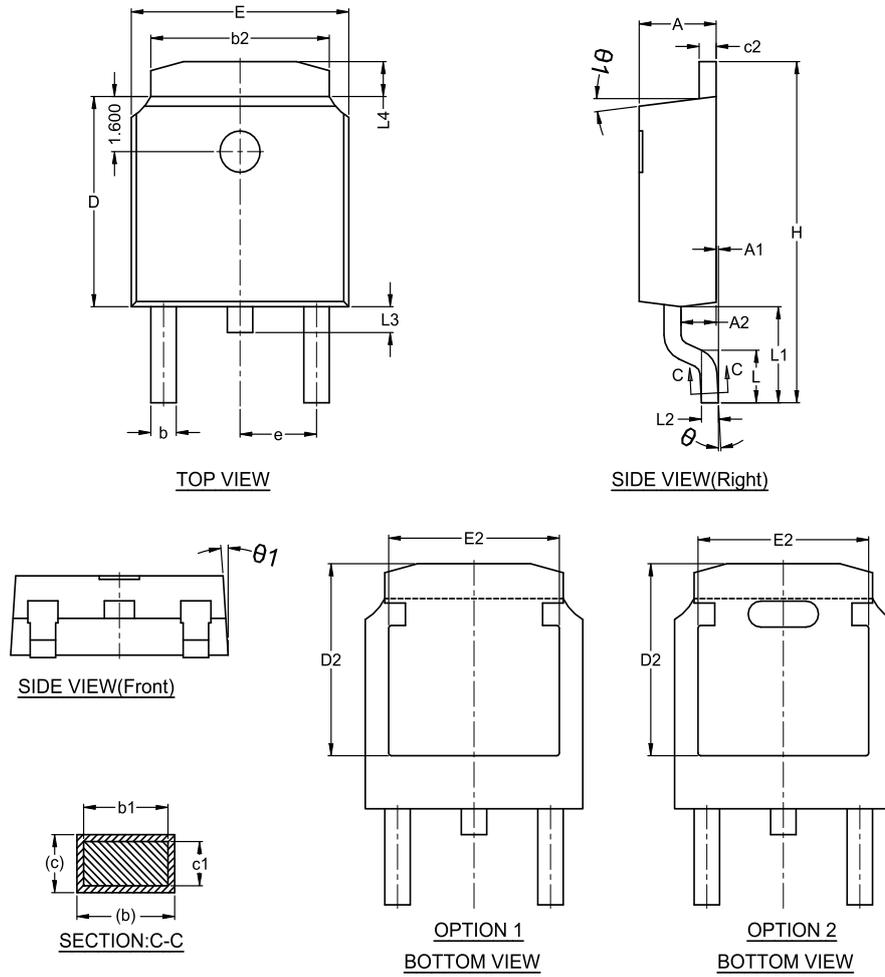
Peak Diode Recovery dv/dt Test Circuit & Waveforms



## Ordering and Marking Information

Ordering Device No.	Marking	Package	Packing	Quantity
ASDM30N120KQ-R	30N120	TO-252	Tape&Reel	2500/Reel

PACKAGE	MARKING
TO-252	 <p>AS    □□    → Lot Number  30N120  □□□□    → Date Code</p>

**TO-252 PACKAGE IN FORMATION**


DIM SYMBOL	MIN.	NOM.	MAX.
A	2.200	2.300	2.400
A1	0.000	0.070	0.130
A2	0.950	1.050	1.150
b	0.700	0.800	0.900
b1	0.660	0.760	0.860
b2	5.134	5.334	5.534
c	0.448	0.548	0.648
c1	0.458	0.508	0.558
c2	0.448	0.548	0.648
D	6.000	6.100	6.200
D2	5.372	5.572	5.772
E	6.400	6.500	6.600
E2	4.900	5.100	5.300
e	2.286 BSC.		
H	9.700	9.900	10.100
L	1.380	1.525	1.725
L1	2.588	2.788	2.988
L2	0.508 BSC.		
L3	0.600	0.750	0.950
L4	0.812	1.012	1.212
$\theta$	1°	3°	5°
$\theta_1$	6°	7°	8°

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